NSN 6625-01-274-4662

Semiconductor Device Test Set - Page 1 of 1



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| End | Λnr | Nica | tion: |
|------|-----|------|-------|
| LIIU | ANK | ліса | uvii. |

Gpete program

Shelf Life:

N/a

Unit Of Measure:

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Demilitarization:

No

Fiig:

T228-a